SEAT No.:
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[Total No. of Pages :2

*P.T.O.* 

## [5670]-598 **B.E.** (**E** &TC)

## VLSI DESIGN & TECHNOLOGY

(2015 Pattern) (Semester-I) (End Sem.) (404181)

Time : 21/	[Max. Mark	cs:70		
Instructions to the candidates:				
1)	Attempt Q.1 or Q.2, Q.3 or Q.4, Q.5 or Q.6, Q.7 or Q.8.			
2)	Neat Diagram must be drawn whenever necessary.			
3)	Figures to the right indicate full marks.			
<i>4</i> )	Assume suitable data if necessary.			
5)	Use of calculator is allowed.			
<b>Q1</b> ) a)	Assume suitable data if necessary.  Use of calculator is allowed.  Explain any two modelling styles in VHDL	[6]		
b)	Explain power distribution & power optimization techniques.	<b>[7</b> ]		
c)	Write features, specifications & applications of CPLD	[7]		
	OR			
<b>Q2</b> ) a)	Write VHDL code and test bench for D flip flop.	[6]		
b)	Explain clock distribution techniques in detail	<b>[7</b> ]		
c)	Draw and explain CLB structure of FPGA device	[ <b>7</b> ] <sub>C</sub>		
		3		
<b>Q3</b> ) a)	Design CMOS combinational logic for y=AB(D+C) and calculate	WŁ		
	ratio of NMOS & PMOS (pull down & pull up)	<b>[8]</b>		
b)	ratio of NMOS & PMOS (pull down & pull up)  Explain  i) Velocity saturation  ii) Hot electron effect  iii) Body effect  iv) channel length modulation	[8]		
	i) Velocity saturation			
	ii) Hot electron effect			
	iii) Body effect			
	iv) channel length modulation			
	OR OR			
<b>Q4</b> ) a)	Explain need for Transmission gate. Draw 4:1 mux using TG	[8]		
b)	Draw CMOS Inverter & explain VTC in detail	[8]		

Q5)	a)	Write spice code for CMOS inverter for AC analysis	[10]
	b)	Explain ASIC design flow in detail	[8]
		OR	
<b>Q6</b> )	a)	Explain micros rules for CMOS layout	[10]
	b)	Explain design issues like antenna effect & electro migration effect	et. [8]
<b>Q</b> 7)	a)	What are types of foult. Explain observability & controllability	[8]
	b)	Write short note on BIST	[8]
		OR 96	
<b>Q</b> 8)	a)	Explain TAP controller with state diagram	[8]
	b)	Explain Boundry scan Architecture	[8]
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